## Notice of References Cited Application/Control No. 09/756,451 Examiner Monica A Fontaine Applicant(s)/Patent Under Reexamination EDWARDS ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,290,248	09-1981	Kemerer et al.	52/309.16
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	-	US-			
	٦	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	Moore, Teffrey A "Evaluation of Environmental Stress Cracking Resistance (ESCR) of High Temperature Clear Plastics for High Voltage Geetnical Devices". Society of Plastics Engineers. 1997.				
	<b>V</b>					
	W					
	x					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.